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FINAL PRODUCT/PROCESS CHANGE NOTIFICATION Generic Copy

Issue Date 19 Dec 2006

SUBJECT: ON Semiconductor Final Product/Process Change Notification #15687

TITLE: Additional Assembly/Test Site Qualification for SMB - Site Previously Qualified

PROPOSED FIRST SHIP DATE: 19 Feb 2007

AFFECTED CHANGE CATEGORY(S): Additional Assembly/Test Site (Previously Qualified)

AFFECTED PRODUCT DIVISION(S): Rectifiers

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION: Contact your local ON Semiconductor Sales Office or <<u>Jim Morgan@onsemi.com</u>>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available Contact your local ON Semiconductor Sales Office or <<u>Rick.Leuvanos@onsemi.com</u>>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 60 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:

This notification is an update (includes 3 additional device types) to a previous Final PCN # 11621 issued by ON Semiconductor.

ON Semiconductor has previously qualified LiteOn Seeful (China) to assemble/test SMB Rectifiers. Reliability Qualification has been performed to AEC-Q101 guidelines and all devices have successfully passed testing.

The purpose for updating this PCN is to add these three devices for additional capacity to support demands and reduce product leadtimes.

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RELIABILITY DATA SUMMARY:

Reliability Test Results: Test Conditions

HTRB Vr=80% Max BiasV, Ta=150degC, 1000 hrs. Temp Cycle Air to Air, -65 to +150C, 1000 cycles Autoclave Ta=121C, RH= 100%, PSIg=15, 96 hrs. H3TRB Vr=85%V, Ta=85C, RH= 85%, 1000 hrs. IOL Ta=25C, If = 0.8A, 2 minutes on/off, 15000 cycles D.P.A. Post H3TRB and Temp Cycle Physical Dimension Per Case Outline Drawing Res. To Solder Heat 260 C, Td=10s

Test Desc.	Interval	Control	Test Lot A	Test Lot B	Test Lot C
HTRB	1000 hrs	0/80	0/80	0/80	0/80
Temp Cycle	1000 cyc	0/80	0/80	0/80	0/80
Autoclave	96 hrs	0/80	0/80	0/80	0/80
H3TRB	1000 hrs	0/80	0/80	0/80	0/80
IOL	15000 cyc	0/80	0/80	0/80	0/80
D. P. A		Pass	Pass	Pass	Pass
Physical Dimension -		Pass	Pass	Pass	Pass
Res. To Solder Heat -		Pass	Pass	Pass	Pass

ELECTRICAL CHARACTERISTIC SUMMARY:

No changes to electrical parametrics or specifications

CHANGED PART IDENTIFICATION:

Devices marked with Date Code 0703 or newer may be from alternate site.

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AFFECTED DEVICE LIST

PART

MBRS240LT3G MBRS2040LT3G MBRS1100T3G